

**Search Notes**

Application/Control No.

10/541,974

Examiner

John E. Chapman

Applicant(s)/Patent under  
Reexamination

MESSER ET AL.

Art Unit

2856

**SEARCHED**

Class	Subclass	Date	Examiner
73	622		
"	623		
"	624		
"	627		
310	334		
"	336	3/19/2007	J

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference Search History Printout		4/27/07	J

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR